MEMS Investor Journal and MEPTEC
3rd Annual MEMS Testing and Reliability Conference
Thursday, October 20, 2011 / Biltmore Hotel, Santa Clara, CA

AGENDA

7:45 am	**Registration opens**
8:30 am	**Welcome and Introduction**
8:45 am – 9:30 am	**Cost of MEMS Testing: A Strategic Perspective** *Mårten Vrånes, Director, MEMS Testing and Reliability, Consulting Services Group, MEMS Investor Journal, Inc.*
9:30 am – 10:15 am	**Semiconductor Wafer Test Technology and Trends: Lessons for MEMS Test Engineers** *Ira Feldman, Principal Consultant, Feldman Engineering Corp.*
10:15 am – 10:45 am	**Break and Exhibits**
10:45 am - 11:30 am	**The Role of Test Data Analysis in Taking MEMS Devices from Initial Characterization to Volume Production** *Dan King, Senior Applications Engineer, Galaxy Semiconductor Solutions*
11:30 am – 12:15 pm	**Operational Reliability of RF MEMS Relays** *Daniel Hyman, President, XCOM Wireless, Inc.*
12:15 pm – 1:15 pm	**Lunch and Exhibits**
1:15 pm – 2:00 pm	**Automotive MEMS Pressure Sensor Reliability Testing** *Tom Nguyen, Founder and CEO, AVsensors, Inc.*
2:00 pm – 2:45 pm	**Bonding Reliability Testing for Wafer-Level Packaged MEMS Devices** *Michael Shillinger, VP of Operations, Innovative Micro Technology, Inc.*
2:45 pm – 3:15 pm	**Break and Exhibits**
3:15 pm – 4:00 pm	**Optical Measurement Techniques for MEMS Characterization** *Eric Lawrence, MEMS Business Development Manager, Polytec Inc.*
4:00 pm – 4:45 pm	**Increased Yield and Reliability of Packaged MEMS Resonator Devices** *Carl Arft, Director, Test Development Engineering, SiTime Corporation*
4:45 pm – 5:00 pm	**Wrap up / additional questions**
5:00 pm – 6:00 pm	**Reception**